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				Application Number	TBD 10/697137
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				First Named Inventor	Jeffrey A. West
				Group Art Unit	TBD
				Examiner Name	TBD
Sheet	1	of	1	Attorney Docket No.	TI-36238

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MG	CA	T. TAKEWAKI et al., "Excellent Electro/Stress-Migration-Resistance Giant-Grain Copper Interconnect Technology for High-Performance Power Devices," Proceedings of 1995 International Symposium on Power Semiconductor Devices & ICs, Yokohama, pp. 438-442.	
MG	CB	S. HYMES et al., "Passivation of copper by silicide formation in dilute silane," J. Appl. Phys. 71 (9), 1 May 1992, pp. 4623-4625.	
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